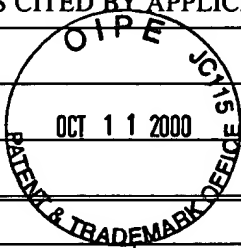
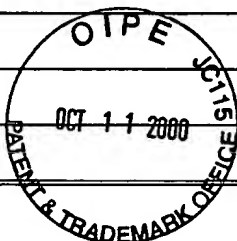


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11/28/2000

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